

Notice of References Cited	Application/Control No. 10/614,031	Applicant(s)/Patent Under Reexamination PAN ET AL.	
	Examiner Andre' C. Stevenson	Art Unit 2812	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,782,302	11-1988	Bastasz et al.	324/71.3
*	B	US-5,219,769	06-1993	Yonehara et al.	438/105
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	"Characteristics of Al/p-CuAgINSe Polycrystalline Thin Film Schottky Barrier Diodes; G Venkata Rao; March 6, 2001 Thin Film Laboratory, Department of Physics, Sri Venkateswara University; Pages 571-576
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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